

## Nanocomp Technologies In-House Testing Capabilities

Imaging Systems		
	SEM (Scanning Electron Microscope)	FEI Quanta 3D
	TEM (Transmission Electron Microscope)	JOEL2010F
	Portable IR imaging camera	FLIR
	Digital microscopes w Image Analysis Capability w Image J	Misc.
	Imaging particle size analyzer	FlowCam
	Stereo and Compound Microscopes	Olympus, Leica
Compositional Analysis		
	Raman spectrometer	Renishaw
	X-Ray Fluorescence Analyzer(XRF)	Rigako Nex-CG
	Gas Chromatograph	Agilent 6890N
	Mass Spectrometer	Agilent 5973N
	TGA's(Thermal Gravimetric Analyzers	TA Instruments
	Ultraviolet-visible absorption spectrometer	Shimadzu UV-2600
	Visible emission spectrometer	Ocean Optics 2000+
	Residual gas analyzer	Extrel
	Chemical Analytical Lab	
	FTIR	Nicolet
Material Characterization		
	100" X 54" Beta film thickness scanner	Mahlo, customized
	Tensile testers	Instron, Zwick
	Viscometers	Brookfield
	Analytical balances including ultramicro balances	Mettler-Toledo, Sartorius
	Non-contact sheet resistivity meter	Delcom
	Thermal characterization equipment	Huxflux, TA, Others
	Digital Goniometer	Rame-Hart
	Density Measurement	Quantachrome UltraPyc 1200 Helium Pycnometer
	Dynamic Mechanical analyzer	TA Instruments
	Speed of Sound Measurement System	Lawson-Hemphill
	Helium Pycnometry	
	IR flux and spectral emission	Custom
Specimen preparation		
	Automated spray coaters	Nordsen, Custom
	Benchtop twin screw compounding extruder	Thermofischer
	Sectioning/polishing system	Struers
	Hot rolling mill	
	400 ton 12" X 12" heated platen hydraulic press	
	Walk-in drying oven	Grieve
	Sputtering system (for SEM and TEM prep)	TA Instruments
	Plasma etcher (for SEM and TEM prep)	TA Instruments
Reliability and Accelerated Aging		
	Solar Aging System	Atlas Materials
	Environmental Test Chamber	Tenny-Lunaire
	Time-at-Temperature ovens	VWR